



Atty. Dkt. No.	M#	Client Ref.
	306781	P-0381.010-US

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: Joeri LOF *et al.*

Appln. No.: Unknown

Filing Date: November 12, 2003

Examiner: Unknown

Group Art Unit: Unknown

Date: November 12, 2003

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Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
P/L	AR 3,573,975	04/1971	Dhaka <i>et al.</i>	117	212	
	BR 3,648,587	03/1972	Stevens	95	44	
	CR 4,346,164	08/1982	Tabarelli <i>et al.</i>	430	311	
	DR 4,396,705	08/1983	Akeyama <i>et al.</i>	430	326	
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	HR 5,121,256	06/1992	Corle <i>et al.</i>	359	664	
	IR 5,610,683	03/1997	Takahashi	355	53	
	JR 5,715,039	02/1998	Fukuda <i>et al.</i>	355	53	
	KR 5,825,043	10/1998	Suwa	250	548	
	LR 5,900,354	05/1999	Batchelder	430	395	
	MR 6,191,429	02/2001	Suwa	250	548	
P/L	NR 6,560,032	05/2003	Hatano	359	656	

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	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
P/L	OR WO 99/49504	09/1999	PCT	Fukami <i>et al.</i>	X		X	
	PR EP 0023231	02/1981	Europe	Tabarelli <i>et al.</i>	X			
	QR EP 0418427	03/1991	Europe	Miyake	X		X	
	RR EP 1039511	09/2000	Europe	Murakimi <i>et al.</i>	X		X	
	SR DD 224448	07/1985	German	Hesse <i>et al.</i>		X		
	TR DD 242880	02/1987	German	Kuch		X		
	UR FR 2474708	07/1981	France	Letellier		X		
	VR JP 62-065326	03/1987	Japan	Moriuchi	X			
	WR JP 62-121417	06/1987	Japan	Nakazawa	X			
P/L	XR JP 63-157419	06/1988	Japan	Nakasuji	X			

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

P/L	YR	EP Search Report for EP 02257938 dated September 25, 2003
	ZR	M. Switkes <i>et al.</i> , "Immersion Lithography at 157 nm", MIT Lincoln Lab, Orlando 2001-1, December 17, 2001
	AAR	M. Switkes <i>et al.</i> , "Immersion Lithography at 157 nm", J. Vac. Sci. Technol. B., Vol. 19, No. 6, November/December 2001, pp. 2353-2356
P/L	BBR	M. Switkes <i>et al.</i> , "Immersion Lithography: Optics for the 50 nm Node", 157 Anvers-1, September 4, 2002

Examiner

Date Considered: 5/23/06

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PK	CCR 6,603,130	08/2003	Bisschops <i>et al.</i>	250	492.1	
	DDR 6,633,365	10/2003	Suenaga	355	53	
	EER 2002/0163629	11/2002	Switkes <i>et al.</i>	355	53	
	FFR 2003/0123040	07/2003	Almogy	355	69	
PK	GGR 2003/0174408	09/2003	Rostalski <i>et al.</i>	359	642	
	HHR					
	IIR					
	JJR					
	KKR					
	LLR					
	MMR					
	NNR					
	OOR					
	PPR					

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	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
PK	QQR JP 04-305915	10/1992	Japan	Ozeki <i>et al.</i>	X			
	RRR JP 04-305917	10/1992	Japan	Ozeki <i>et al.</i>	X			
	SSR JP 06-124873	05/1994	Japan	Takahashi	X		X	
	TTR JP 07-220990	08/1995	Japan	Fukuda <i>et al.</i>	X			
	UUR JP 10-228661	08/1998	Japan	Kurokawa	X			
	VVR JP 10-255319	09/1998	Japan	Suenaga <i>et al.</i>	X			
	WWR JP 10-303114	11/1998	Japan	Suwa	X		X	
	XXR JP 10-340846	12/1998	Japan	Kudo	X		X	
PK	YYR JP 2001-091849	04/2001	Japan	Aizaki <i>et al.</i>	X			
	ZZR							

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PK	AAAR	B.J. Lin, "Drivers, Prospects and Challenges for Immersion Lithography", TSMC, Inc., September 2002			
PK	BBBR	B.J. Lin, "Proximity Printing Through Liquid", IBM Technical Disclosure Bulletin, Vol.20, No. 11B, April 1978, p. 4997			

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	CCC					
	DDD					
	EEE					

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		FFFF								
		GGG								

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PH	HHH	B.J. Lin, "The Paths To Subhalf-Micrometer Optical Lithography", SPIE Vol. 922, Optical/Laser Microlithography (1988), pp. 256-269				
	IIIR	G.W.W. Stevens, "Reduction of Waste Resulting from Mask Defects", Solid State Technology, August 1978, Vol.21 008, pp. 68-72				
	JJRR	S. Owa <i>et al.</i> , "Immersion Lithography; its potential performance and issues", SPIE Microlithography 2003, 5040-186, February 27, 2003				
	KKK	S. Owa <i>et al.</i> , "Advantage and Feasibility of Immersion Lithography", Proc. SPIE 5040 (2003)				
	LLL	Nikon Precision Europe GmbH, "Investor Relations - Nikon's Real Solutions", May 15, 2003				
	MMM	H. Kawata <i>et al.</i> , "Optical Projection Lithography using Lenses with Numerical Apertures Greater than Unity", Microelectronic Engineering 9 (1989), pp. 31-36				
	NNN	J.A. Hoffnagle <i>et al.</i> , "Liquid Immersion Deep-Ultraviolet Interferometric Lithography", J. Vac. Sci. Technol. B., Vol. 17, No. 6, November/December 1999, pp. 3306-3309				
	OOO	B.W. Smith <i>et al.</i> , "Immersion Optical Lithography at 193nm", FUTURE FAB International, Vol. 15, July 11, 2003				
	PPP	H. Kawata <i>et al.</i> , "Fabrication of 0.2µm Fine Patterns Using Optical Projection Lithography with an Oil Immersion Lens", Jpn. J. Appl. Phys. Vol. 31 (1992), pp. 4174-4177				
PK	QQQ	G. Owen <i>et al.</i> , "1/8µm Optical Lithography", J. Vac. Sci. Technol. B., Vol. 10, No. 6, November/December 1992, pp. 3032-3036				
	RRR					
	SSS					
	TTT					
	UUU					
	VVV					
	WWW					
	XXX					
	YYY					

Examiner

John J. Kim

Date Considered:

5/23/06

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	QR EP 0418427	03/1991	Europe	Miyake	X		X	
	RR EP 1039511	09/2000	Europe	Murakimi <i>et al.</i>	X		X	
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	TR DD 242880	02/1987	German	Kuch		X		
	UR FR 2474708	07/1981	France	Letellier		X		
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FORM PTO-1449 (modified)
To: U.S. Department of Commerce
(PW FORM PAT-1449)
Patent and Trademark Office

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	KR 5,825,043	10/1998	Suwa	250	548	
	LR 5,900,354	05/1999	Balchender	430	395	
	MR 5,191,429	02/2001	Suwa	250	548	
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QR	EP 0418427	03/1991	Europe	Miyake	X		X	
RR	EP 1038511	08/2000	Europe	Murakimi et al.	X		X	
SR	DD 224448	07/1985	German	Hesse et al.		X		
TR	DD 242880	02/1987	German	Kuch		X		
UR	FR 2474708	07/1981	France	Leterrier		X		
VR	JP 62-085326	03/1987	Japan	Moriuchi	X			
WR	JP 62-121417	06/1987	Japan	Nakazawa	X			
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